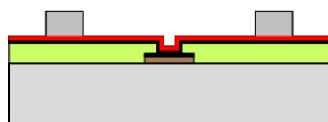


- o Status of UBM Development (3rd Metal layer in Cu)
- o Ladder geometry
 - : Micro joint for layer 2 (and 1??)
 - : Geometry
 - : Plans for dummies

- : Assuming we get bumps on the ASICs - Pactech machine or already bumped by IBM/external bumping services – we still need a solderable pad on the sensor!
- : two options:
 - a. coined gold studs directly on Alu
 - b. Landing pad Cu/Sn by electroplating at HLL
- : for PXD6 we have to use option a.
→ if this works, it can well be used also for the final run
- : but keep option b. open, it is effectively a 3rd metal layer, which we might need at the end

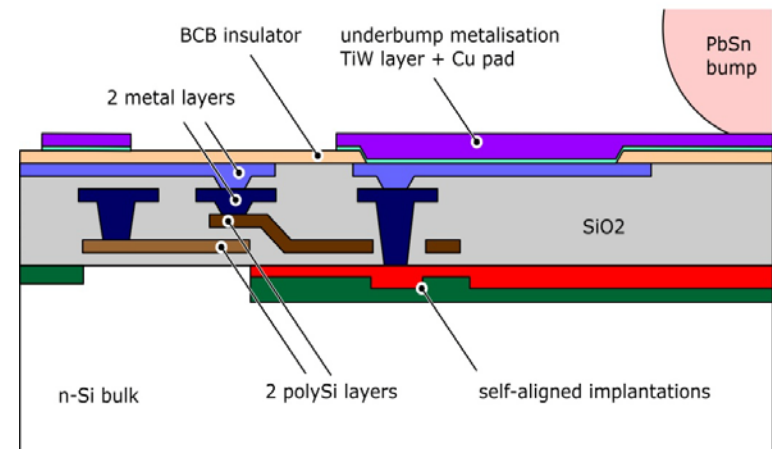
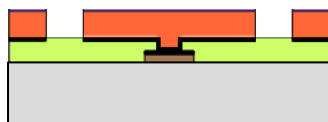


Sputtering
TiW barrier 50nm
Cu seedlayer 100nm

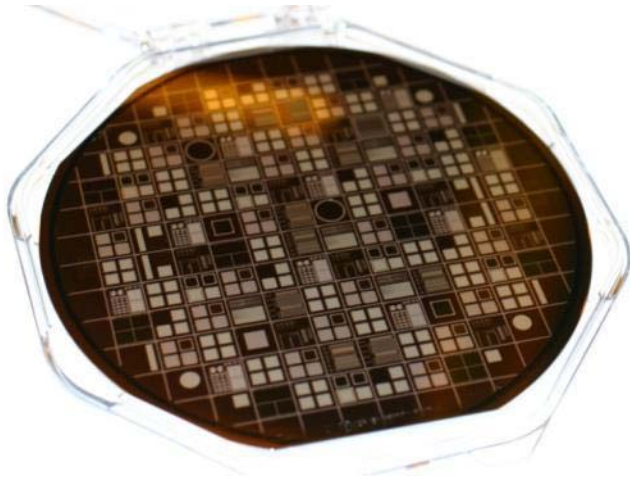
Litho
Insulation trenches

Plating module
Cu 5µm

Resist strip
Wet etch seedlayer & barrier



● Small Project with CNM → Cu layer on HLL test diodes



at HLL:

a. Pre-processing of 3 SOI and 3 Std. up to BCB openings
PiN Diodes, MOS Caps. many test structures for:

- design rules
- contact and sheet resistance
- contact "chains"

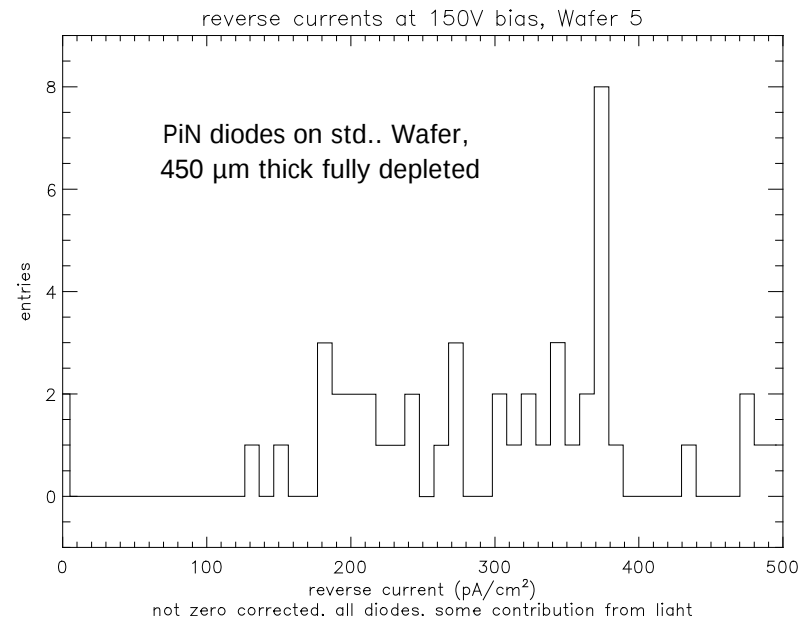
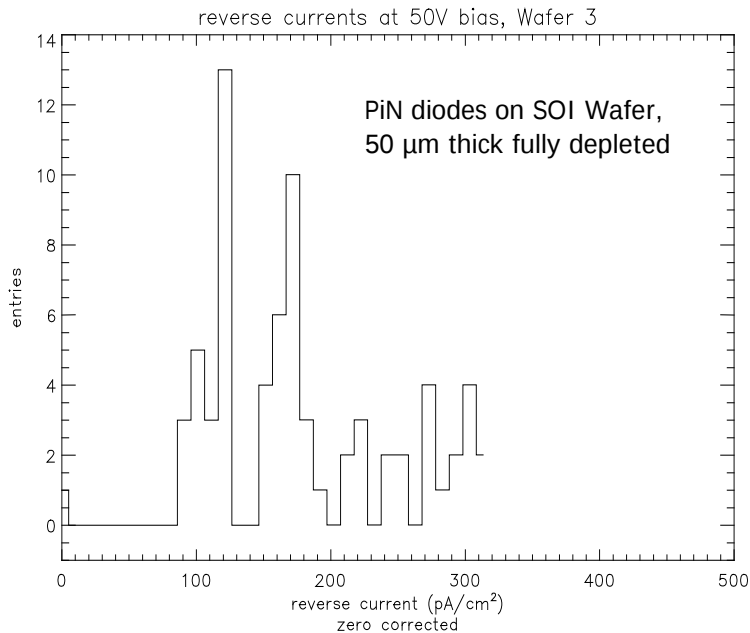
b. characterization before Cu

-: at CNM, Barcelona :

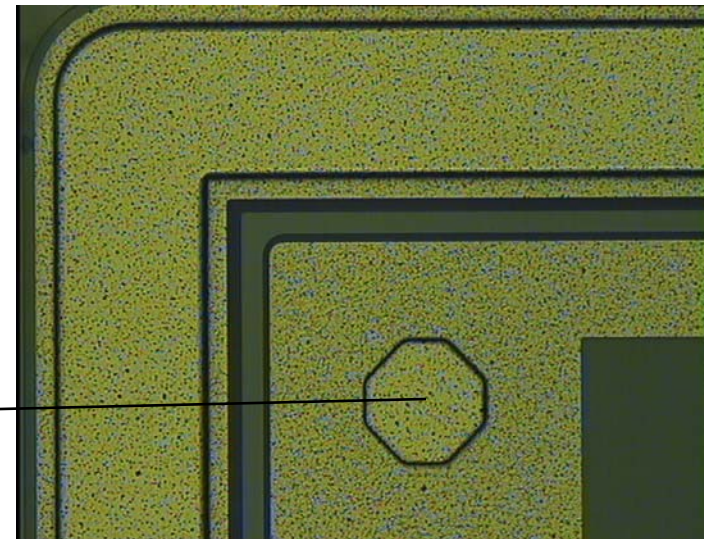
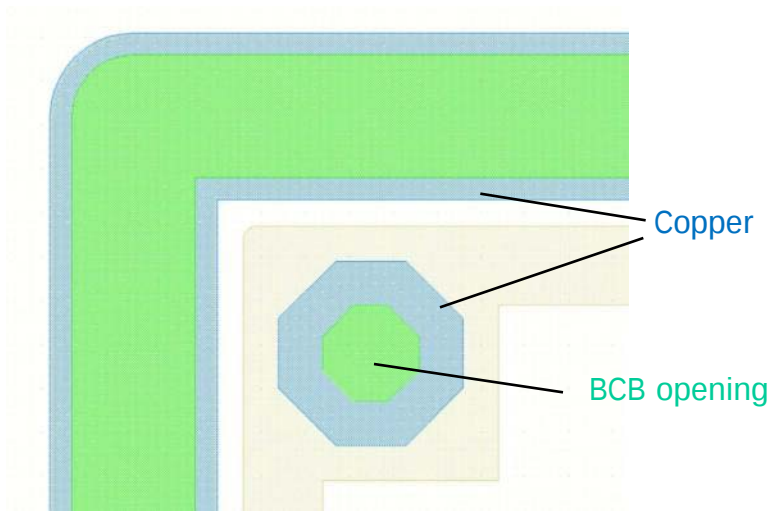
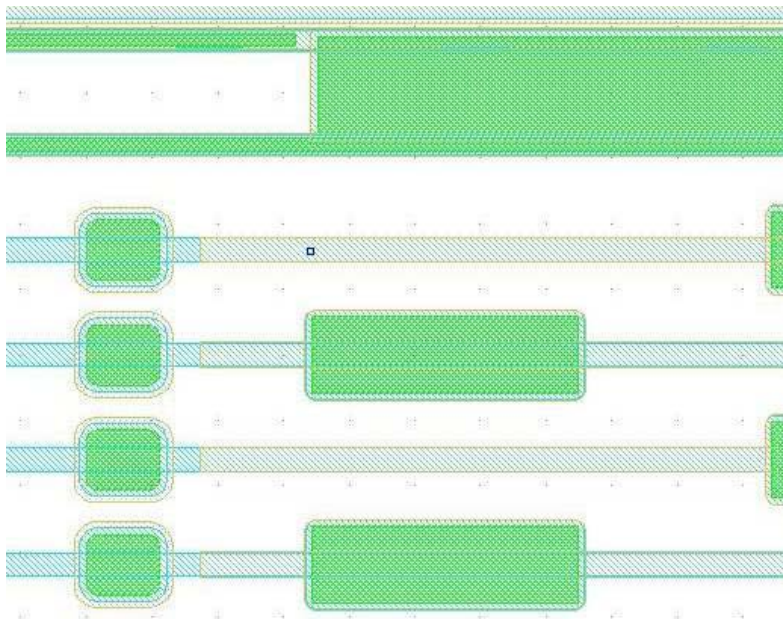


a. sputter barrier and seed layer

b. thru mask electroplating of Cu → ongoing



● A few details: mask and real world



UBM Process

1. Sputter Ti:W und Cu (externally at the beginning)
2. Lithography: thick photo resist
3. Thru mask EP: 3-5 μm Cu, ca. 2-3 μm Sn
4. Resist strip
5. wet etch Cu
6. Wet etch Ti:W: H_2O_2 (with additives)

→ install step 2.-6. at HLL

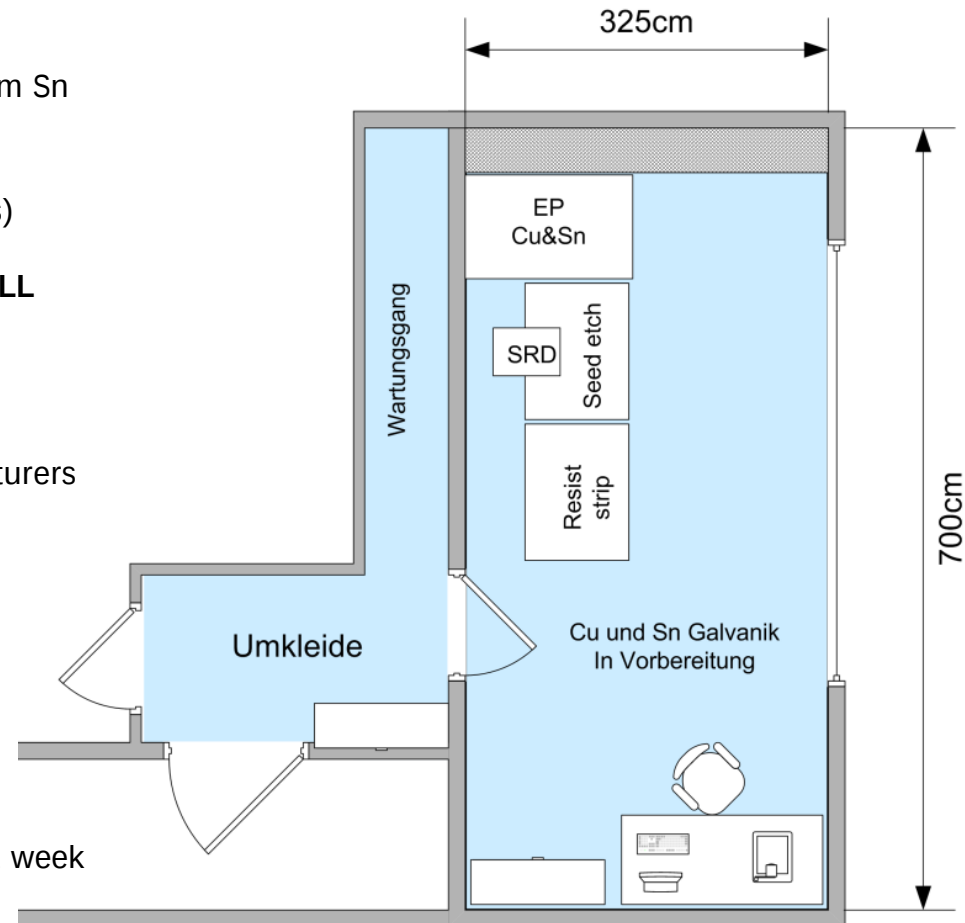
Result after....

- : a lot of discussions with two equipment manufacturers
- : consultation of process experts and chemical suppliers for electro-plating

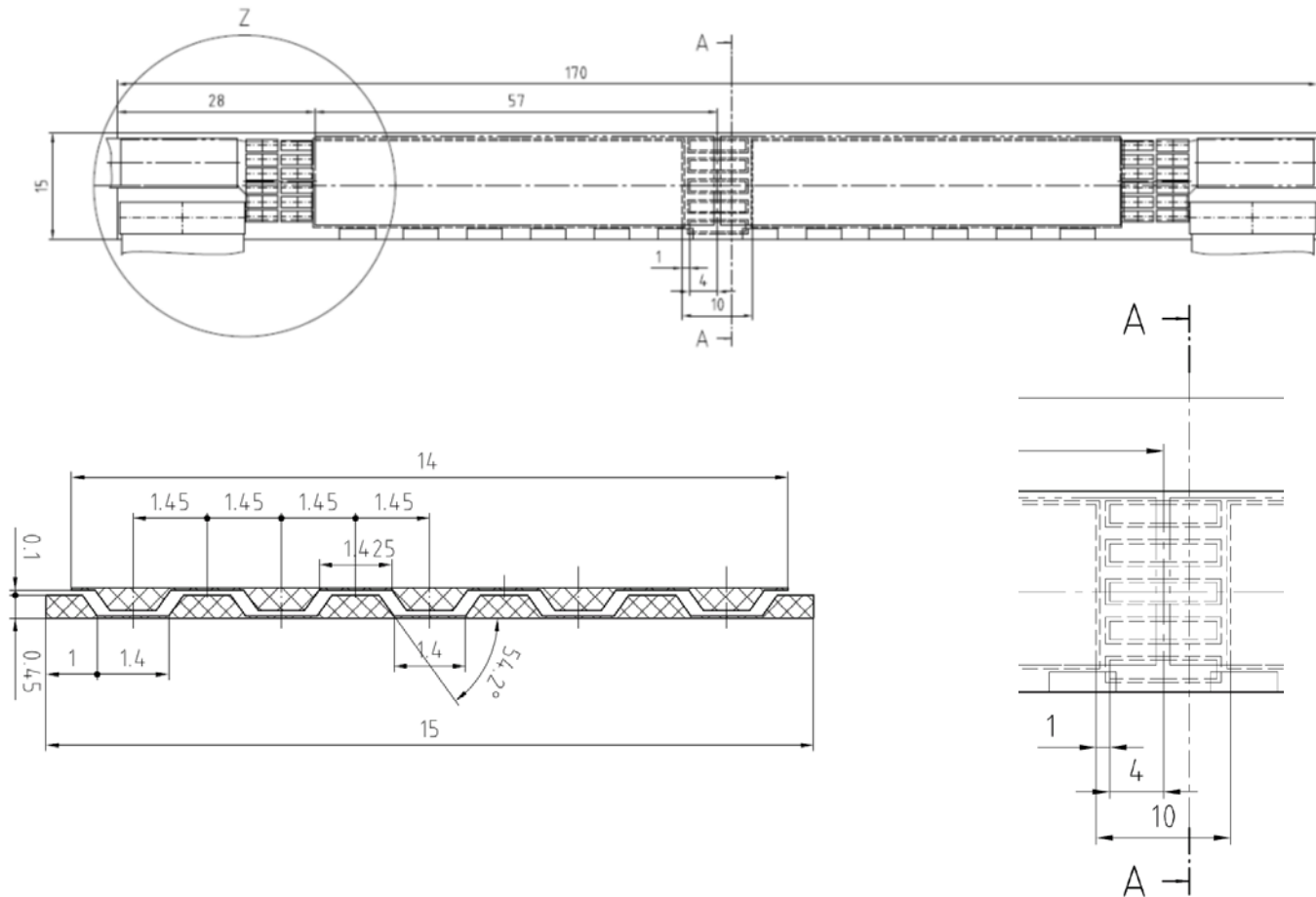
- Fountain plater for Cu and Sn,
- etch baths for seed layer removal,
- solvent wet bench

Status: - configuration and negotiations finished
- formal "call for bids" to be sent out next week
- delivery early 2010

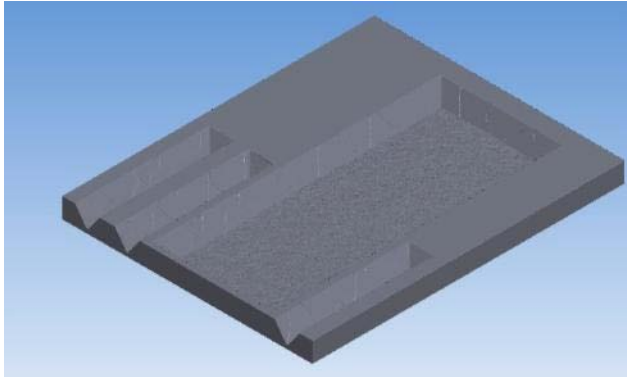
Start Process installation Q1 2010



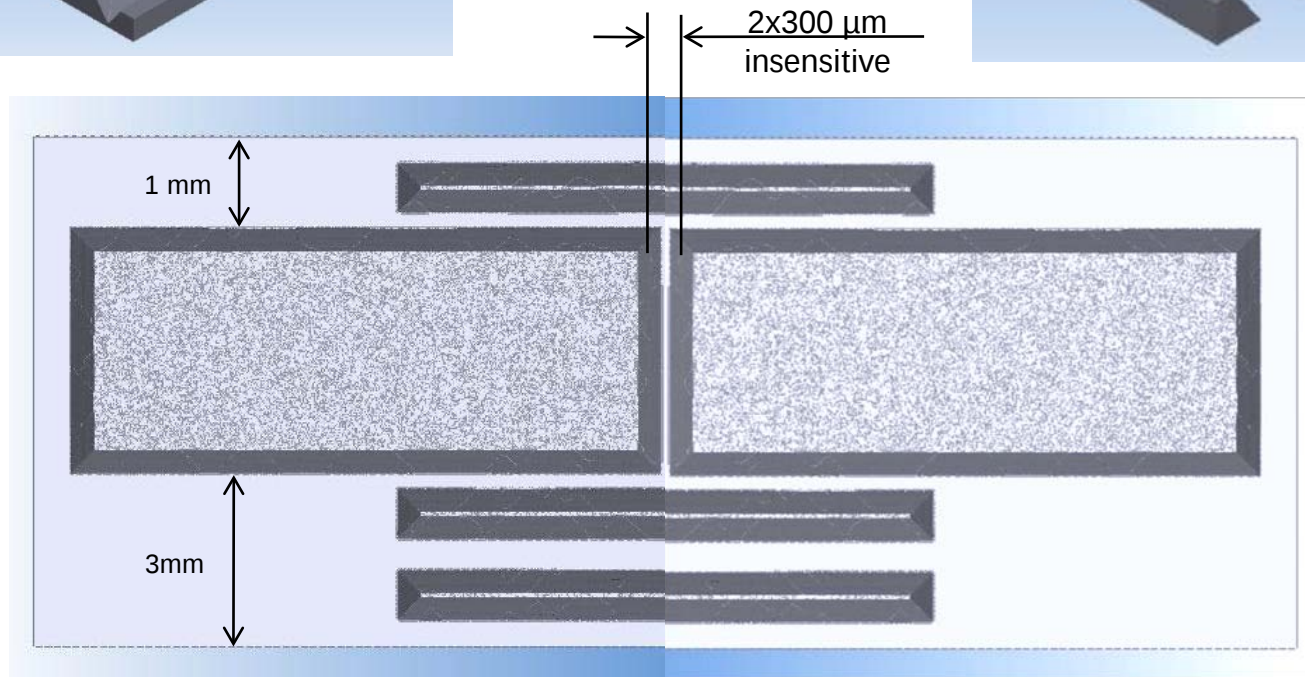
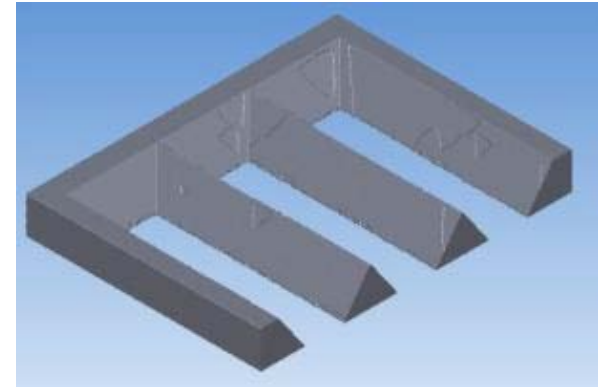
- Current ladder design (V06a) → joint in layer 2



- joint in layer 2 → new proposal



Low-mass joint between two
Ladders at the second layer of
Belle II PXD...

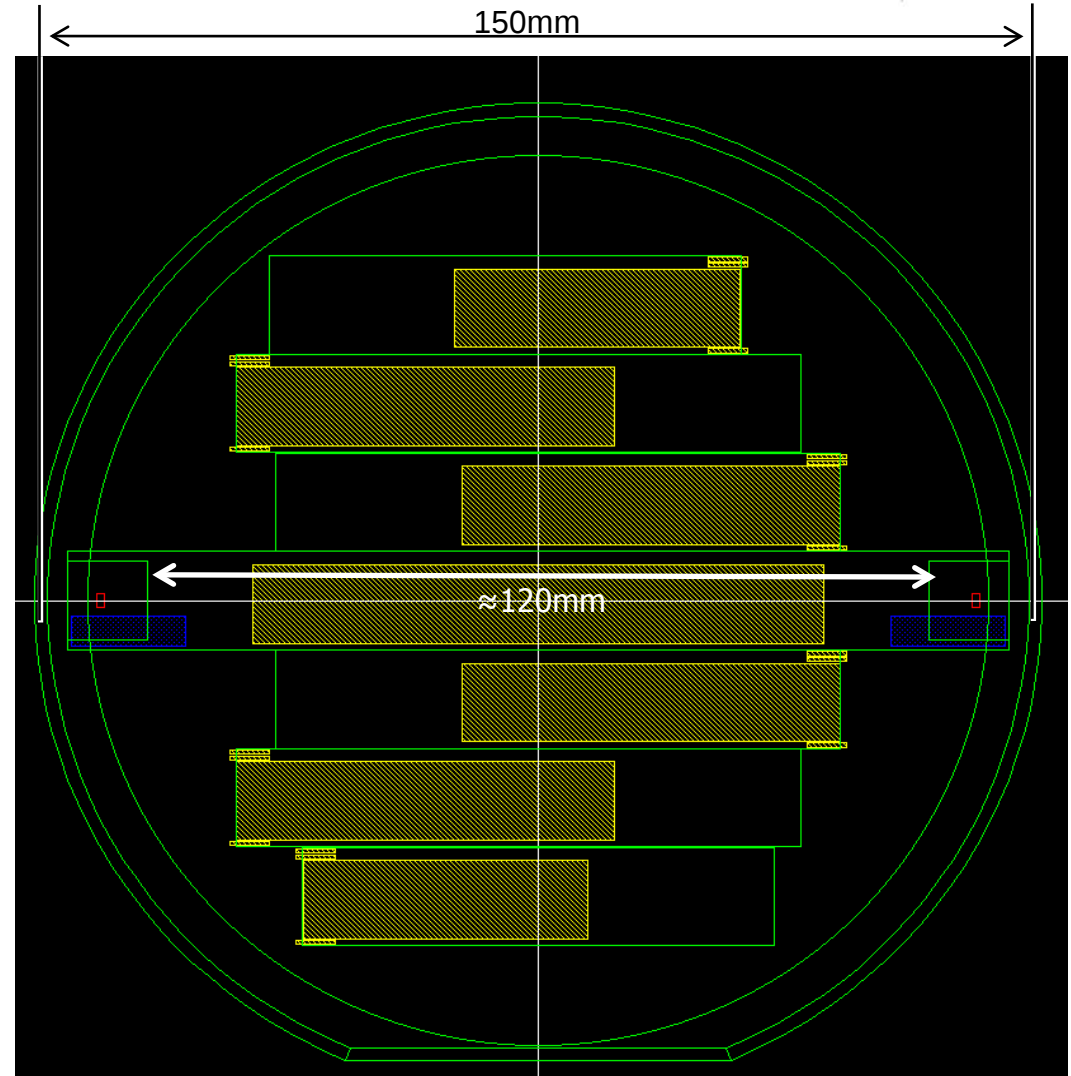
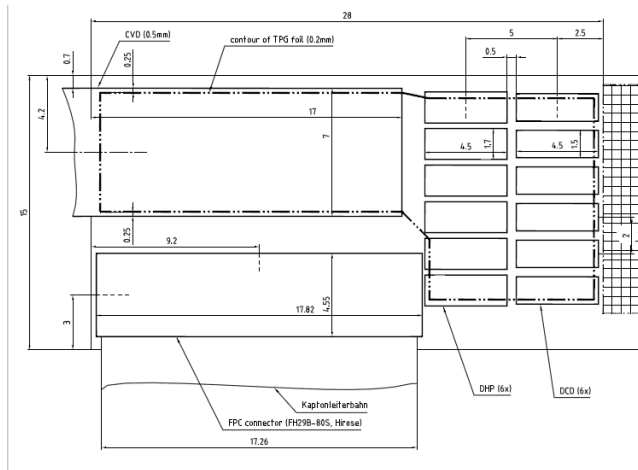


Would this be acceptable in the first layer also???

● Current ladder design (V06a)

- length of layer 1: 142 mm!!!
- with metal traces for connector

Because of alignment structures
metal layers only possible for ≈ 120 mm,
Ladder can be longer, but no structured
metal beyond ± 60 mm from center !



→ Hans: Table of Signals and Supplies

	name	type	voltage [V]	current [mA]	comment	diff.	thin	thick	k
digital signals	GCK	LVDS in				1			
	FCK	LVDS in				1			
	TRG	LVDS in				1			
	RST	LVC MOS in					1		
	TMS	LVC MOS in					1		
	TDI	LVC MOS in					1		
	TCK	LVC MOS in					1		
	TDO	LVC MOS out					1		
	DO[5:0]	CML out				6			
23 digital signals									
power supplies	VDDA	DCD analog	1,8	600	sense line		1	6	
DCD	VDDD	DCD digital	1,8	250	sense line		1	2	
	REFIN	DCD analog ref	1,1	100	sense line		1	2	
	DGND	common digital ground	0	1000	sense line		1	10	
	AGND	analog ground	0	600	sense line		1	6	
42 Power lines incl. sense lines									
DHP	VDDIO	DHP IO rail	1,8	100	sense line		1	2	
	VDDC	DHP core	1	500	sense line		1	5	
SWITCHER	VDDS	digital supply	3,3	10	sense line?			1	
	AVDDS	analog supply ?	20	?	sense line?			2	
bias voltages	Vclear_on	clear on	-0				1		
	Vclear_off	clear off	-1				1		
	Vgate_on	gate on	-2				1		
	Vgate_off	gate off	-3				1		
	Vsource	source	7	30			1	1	
	Vccg	common clear gate	-0				1		
	Vbulk	bulk	10				1		
	Vbias	backplane	-20				1		
10 sensor bias									
number of signal pins:						18	20	37	
total sum:								75	

preliminary list, included sense lines

not included yet:

NTC

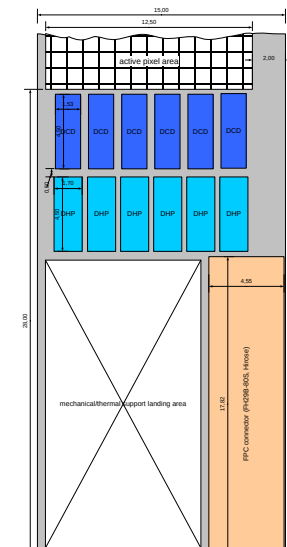
JTAG with LVDS instead of

LVC MOS

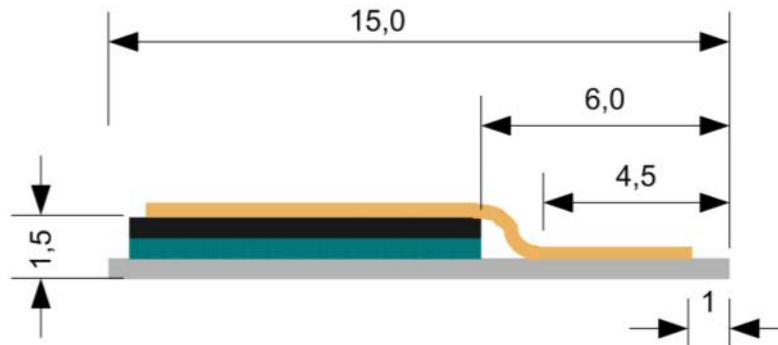
Vedge for DEPFET matrix

→ minimum requirement: 75 contacts

→ Hirose 80 pin conn. with $l \approx 18 \text{ mm}$



● End of Stave: Connector??↔Flex lead??



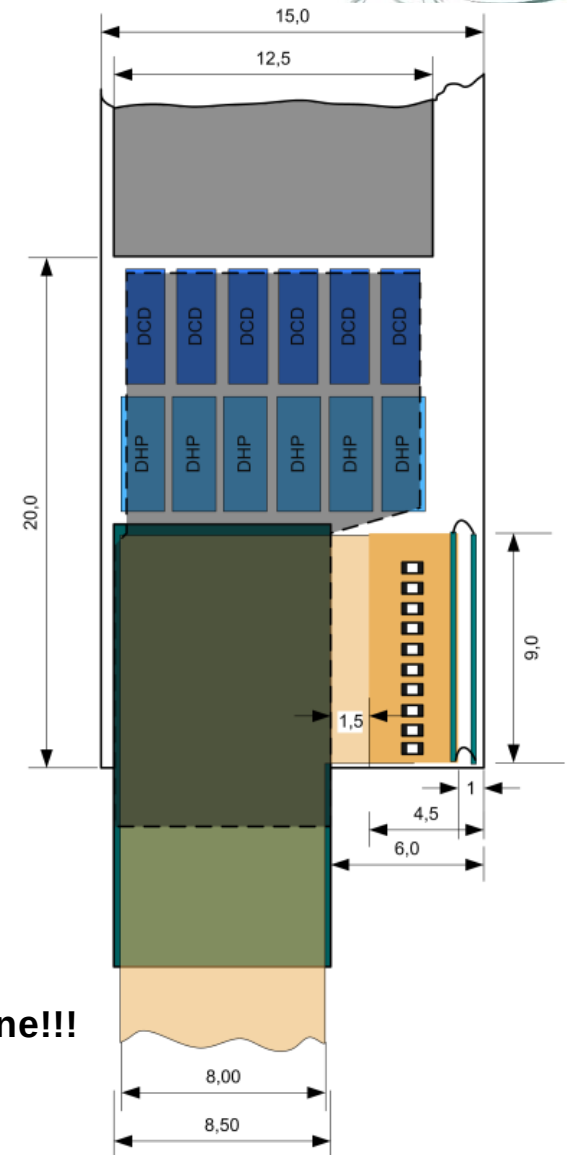
- : Custom made multi-Layer std. Cu flex cable with "several" power and ground layers
- : bendable 2x90° over 1.5 mm lateral and vertical
- : wire bond pads on one end (Au or Ni) min. pitch 100 µm (staggered??), 80 pins
- : connector (flex-flex??) at the far end
- : solderable pads for passive components
- : what bond wire diameter??? And many more questions ...

→ Contact flex hybrid supplier (Dyconex etc.)

EOS: 28→20 mm, L: 142 → 126 mm with 86 mm sensitive

If we reduce the sensitive length from 86 to 80 mm ,we are done!!!

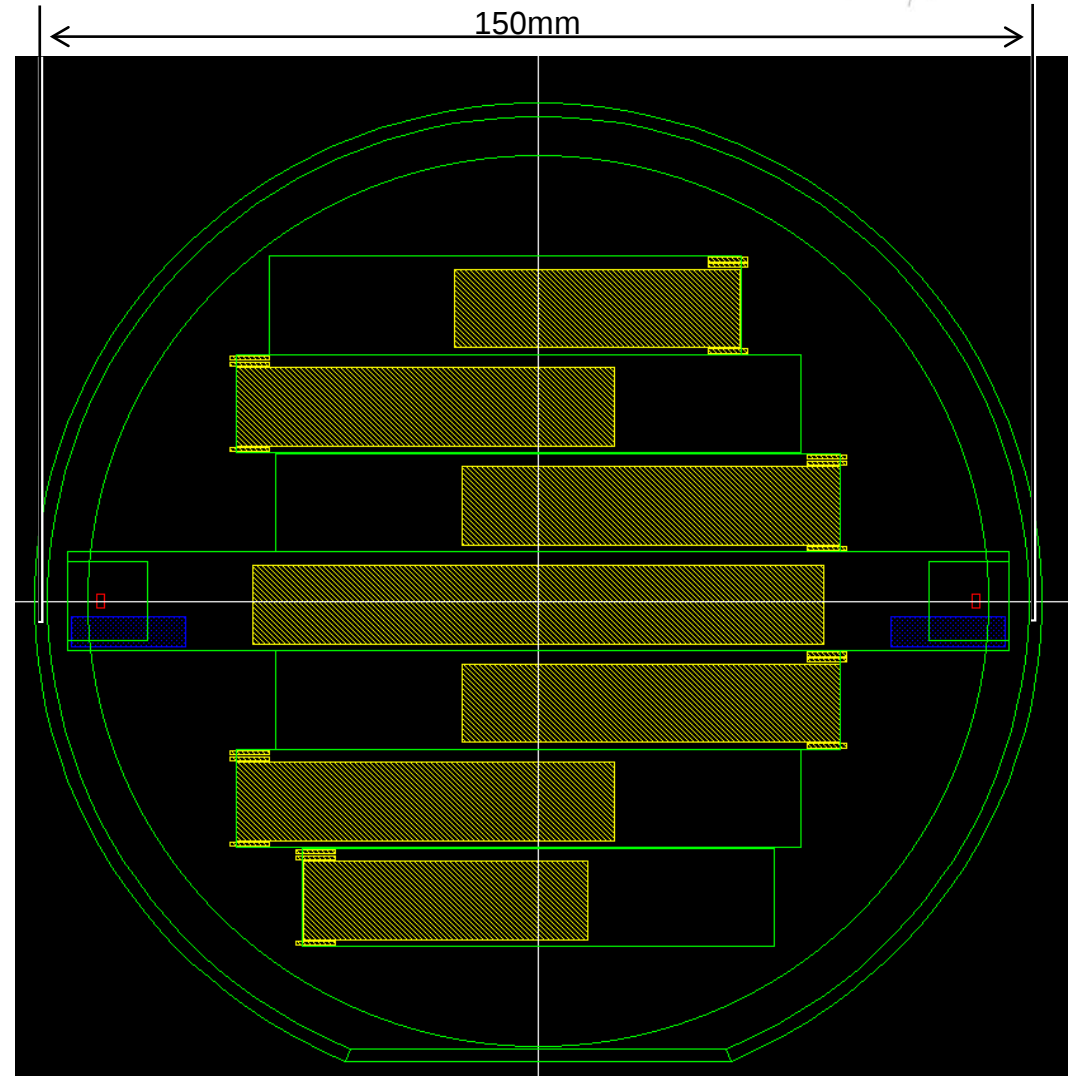
Is this possible???



● Finally, for the dummies:

We are ready:

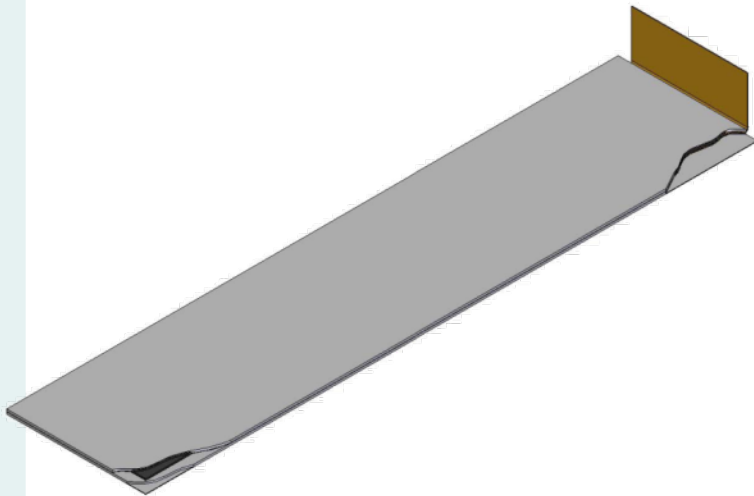
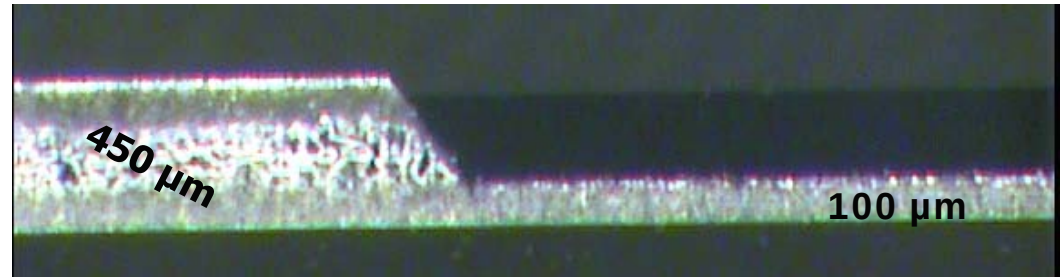
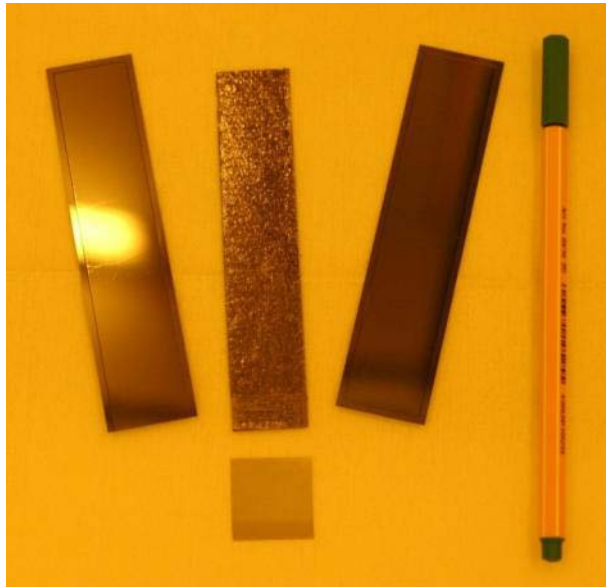
- : metalized mechanical grade are in the cup board
- : as soon as we have defined the dimensions, I could start with the masks (together with Christian..)
- : By the end of this year we could have dummies, both for electrical and thermo-mechanical tests



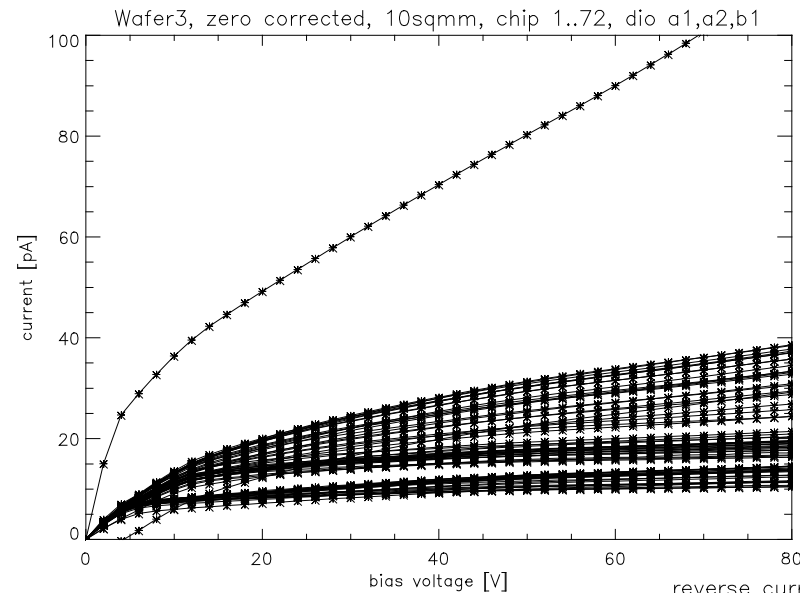
Backup slides follow



- Silicon – TCPG Sandwich



IV before Cu



SOI Wafer,
10mm² diodes,
50 μ m thick,
fully depleted at 50 V

